Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/616,262	WANG ET AL.	
Examiner	Art Unit	
Douglas N. Washburn	2863	

	SEARCHED			
Class	Subclass	Date	Examiner	
702	142	1/31/2006	WND W	
702	145	1/31/2006	DNW	
L	L	L	L	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
702	145	1/31/2006	WND
702	142	1/31/2006	DNW

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST keyword/keyphrase - Update- see printout - (USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	1/31/2006	DNW tw
G06F015/00 - Update- see printout - (USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	1/31/2006	DNW W
702/142, 145 - Update- see printout - (USPGPUB; USPAT; USOCR)	1/31/2006	DNW W
IEEE keyword/keyphrase	1/31/2006	DNW W